

Substitute Form PTO-1449  
(Modified)U.S. Department of Commerce  
Patent and Trademark OfficeAttorney's Docket No.  
07977-023002Application No.  
08/907,182**Information Disclosure Statement  
by Applicant**

(Use several sheets if necessary)

(37 CFR §1.98(b))

Applicant  
Yamazaki, et al.Filing Date  
August 6, 1997Group Art Unit  
1753**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
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	AH						
	AI						
	AJ						
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**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

**Other Documents (include Author, Title, Date, and Place of Publication)**

Examiner Initial	Desig. ID	Document
ADD	AQ	Nakame, M. et al. "Reduction of phosphorous gettering temperature with back side mechanical damage." Ext. Abst. Ecs. Fall Meeting, Vol. 181-2 (1981): 967-968.
	AR	
	AS	
	AT	

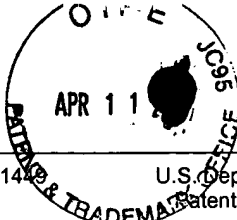
Examiner Signature

Alan D. Dind

Date Considered

5/8/03

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



<b>Substitute Form PTO-1449</b> (Modified)  <b>Information Disclosure Statement</b> <b>by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))	<b>U.S. Department of Commerce</b> <b>Patent and Trademark Office</b>	<b>Attorney's Docket No.</b> 07977-023002	<b>Application No.</b> 08/907,182
	<b>Applicant</b> Yamazaki, et al.		
	<b>Filing Date</b> August 6, 1997	<b>Group Art Unit</b> 1753	

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
ADD	AA	6,475,840 B1	11/5/2002	Miyanaga, et al.	438	166	
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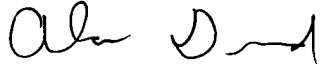
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